March 2002

## FDS4935A

**FAIRCHILD** 

### Dual 30V P-Channel PowerTrench<sup>®</sup> MOSFET

### **General Description**

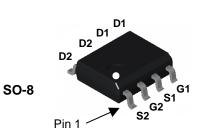
This P-Channel MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications requiring a wide range of gave drive voltage ratings (4.5V - 20V).

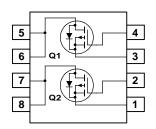
### Applications

- Power management
- Load switch
- Battery protection

### Features

- -7 A, -30 V  $R_{DS(ON)} = 23 \text{ m}\Omega @ V_{GS} = -10 \text{ V}$  $R_{DS(ON)} = 35 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$
- Low gate charge (15nC typical)
- Fast switching speed
- + High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





### Absolute Maximum Ratings T<sub>A=25°C</sub> unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DSS</sub>	Drain-Sour	ce Voltage		-30	V
V <sub>GSS</sub>	Gate-Sourc	e Voltage		±20	V
ID	Drain Curre	ent – Continuous	(Note 1a)	-7	А
		– Pulsed		-30	
PD	Power Dissipation for Dual Operation			2	
PD	Power Diss	ipation for Single Operation	n (Note 1a)	1.6	W
			(Note 1b)	1	
			(Note 1c)	0.9	
T <sub>J</sub> , T <sub>STG</sub>	Operating a	and Storage Junction Tem	-55 to +175	°C	
Therma	l Charac	teristics			
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		pient (Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case (Note 1)		e (Note 1)	40	°C/W
Packag	e Markin	g and Ordering	Information		
Device Marking		Device	Reel Size	Tape width	Quantity
FDS4935A		FDS4935A	13"	12mm	2500 units

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics					
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = -250 \mu A$	-30			V
<u>ΔBVdss</u> ΔTj	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu$ A, Referenced to 25°C		-24		mV/°C
DSS	Zero Gate Voltage Drain Current	$V_{\text{DS}} = -24 \text{ V}, \qquad V_{\text{GS}} = 0 \text{ V}$			-10	μA
GSSF	Gate-Body Leakage, Forward	$V_{GS} = -20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			-100	nA
GSSR	Gate–Body Leakage, Reverse	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	-1	-1.6	-3	V
<u>ΔVgs(th)</u> ΔTj	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		4.4		mV/°C
RDS(on)	Static Drain–Source On–Resistance	$ \begin{array}{l} V_{GS} = -10 \ V,  I_D = -7 \ A \\ V_{GS} = -4.5 \ V,  I_D = -5.5 \ A \\ V_{GS} = -10 \ V, \ I_D = -7 \ A, \ T_J = 125^\circ C \end{array} $		19 28 26	23 35 34	mΩ
D(on)	On–State Drain Current	$V_{GS} = -10 \text{ V}, \qquad V_{DS} = -5 \text{ V}$	-30			А
FS	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_D = -7 \text{ A}$		19		S
Dynamic	Characteristics		•	•	•	•
Ciss	Input Capacitance	$V_{DS} = -15 \text{ V},  V_{GS} = 0 \text{ V},$		1233		pF
Coss	Output Capacitance	f = 1.0 MHz		311		pF
Crss	Reverse Transfer Capacitance	1		152		pF
Switchin	g Characteristics (Note 2)		•	•	•	•
d(on)	Turn–On Delay Time	$V_{DD} = -15 V$ , $I_D = -1 A$ ,		13	23	ns
r	Turn–On Rise Time	$V_{GS} = -10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	20	ns
d(off)	Turn–Off Delay Time			48	77	ns
-() f	Turn–Off Fall Time			25	40	ns
$\mathbf{Q}_{g}$	Total Gate Charge	$V_{DS} = -15 \text{ V}, \qquad I_{D} = -7 \text{ A},$		15	21	nC
$\hat{\boldsymbol{\lambda}}_{gs}$	Gate-Source Charge	$V_{GS} = -5 V$		4.4		nC
$\mathcal{Q}_{qd}$	Gate–Drain Charge			4.5		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings				
s	Maximum Continuous Drain–Source				-2.1	А
√ <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$ , $I_{S} = -2.1 A$ (Note 2)		-0.75	-1.2	V
V <sub>SD</sub> otes: R <sub>eJA</sub> is the sun	Drain–Source Diode Forward	$V_{GS} = 0$ V, $I_S = -2.1$ A (Note 2) mal resistance where the case thermal reference	is defined :		-1.2	V



a) 78°C/W when mounted on a 0.5in<sup>2</sup> pad of 2 oz copper

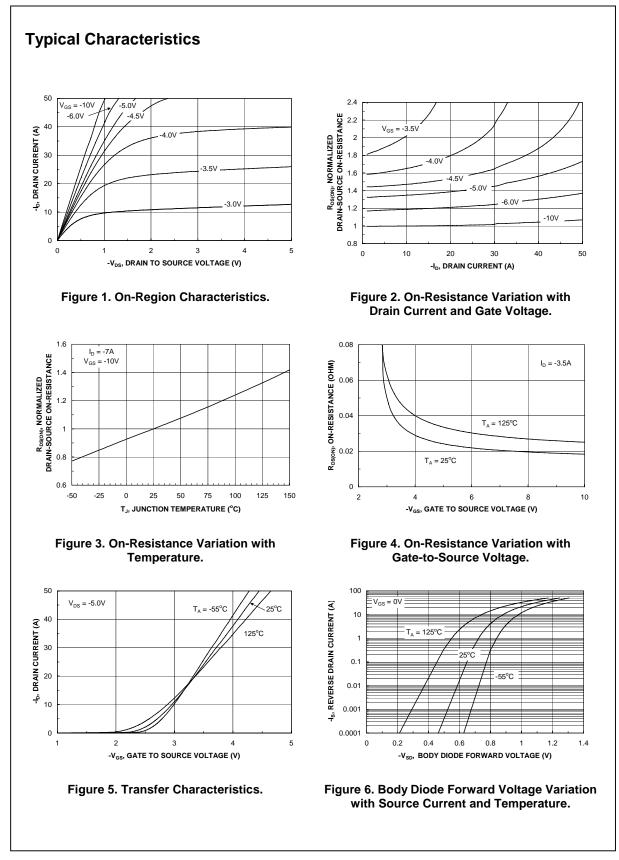
b) 125°C/W when mounted on a 0.02 in<sup>2</sup> pad of 2 oz copper

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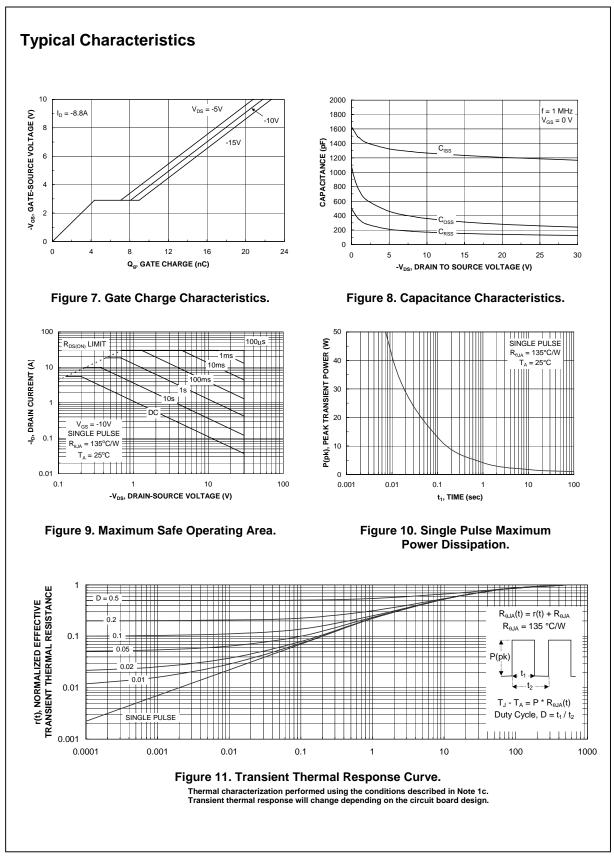
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Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%



# FDS4935A



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FDS4935A Rev A(W)

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